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(Based on PTO 04-07 version)

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)			Complete If Known		
			Application Number	10/518,284-Conf. #3519	
			Filing Date	September 2, 2005	
			First Named Inventor	Peter Hoghoj	
			Art Unit	2882	
			Examiner Name	C. C. G. Kao J. Yun	
Sheet	1	of	2	Attorney Docket Number	XENOCs 3.3-002

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (If known)			
	AA*	US-5,999,262-A	12-07-1999	Dobbs et al.	
	AB*	US-6,317,483-B1	11-13-2001	Chen	
	AC*	US-5,789,036-A	08-25-1998	Gutman	
	AD*	US-6,278,764	08-21-2001	Barbee, Jr. et al.	
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	AG*	US-4,562,583-A	12-31-1985	Hoover et al.	
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Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ²
		Country Code ³ -Number ⁴ -Kind Code ⁵ (If known)	MM-DD-YYYY			
04	BA	EP-0115892	08-15-1984	Philips Nv		✓
04	BB	WO-02/103710-A2	12-27-2002	X-Ray Optical Systems, Inc.		✓
04	BC	GB-2217036-A	10-18-1989	Rosser		✓
04	BD	WO-108162	02-01-2001	Univ California		✓

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. * CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.98(e)(2)(ii)) because that application was filed after June 30, 2003 or is available in the IFV. * Applicant's unique citation designation number (optional). * See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 801.04. * Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). * For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. * Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. * Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		T ²
JY.	CA	NAUDON et al., "New Apparatus for Grazing Reflectometry in the Angle-Resolved Dispersive Mode", J. Appl. Cryst, Vol. 22, Part 5, pp. 460-464, October 1, 1989.		
JY.	CB	M.P. Ulmer, Production and performance of multilayer coated conic sections, Jul 2001, SPIE, Vol. 4496, page 127-133.		
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JY.	CG	G.E. ICE, "Microbeam Forming Methods for Synchrotron Radiation," © 1997		

Examiner Signature 772863	Juric Yun	Date Considered	6-19-07
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